

**Search Notes**

Application/Control No.

10/661,638

Examiner

Lois Zheng

Applicant(s)/Patent under  
Reexamination

HIRAIWA ET AL.

Art Unit

1742

**SEARCHED**

Class	Subclass	Date	Examiner
204	287	2/2/2007	LLZ
205	619	2/2/2007	LLZ
205	620	2/2/2007	LLZ

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
inventorship search	2/2/2007	LLZ
Updated EAST search	2/2/2007	LLZ